

TYPES 2N5225, A5T5225 N-P-N SILICON TRANSISTORS

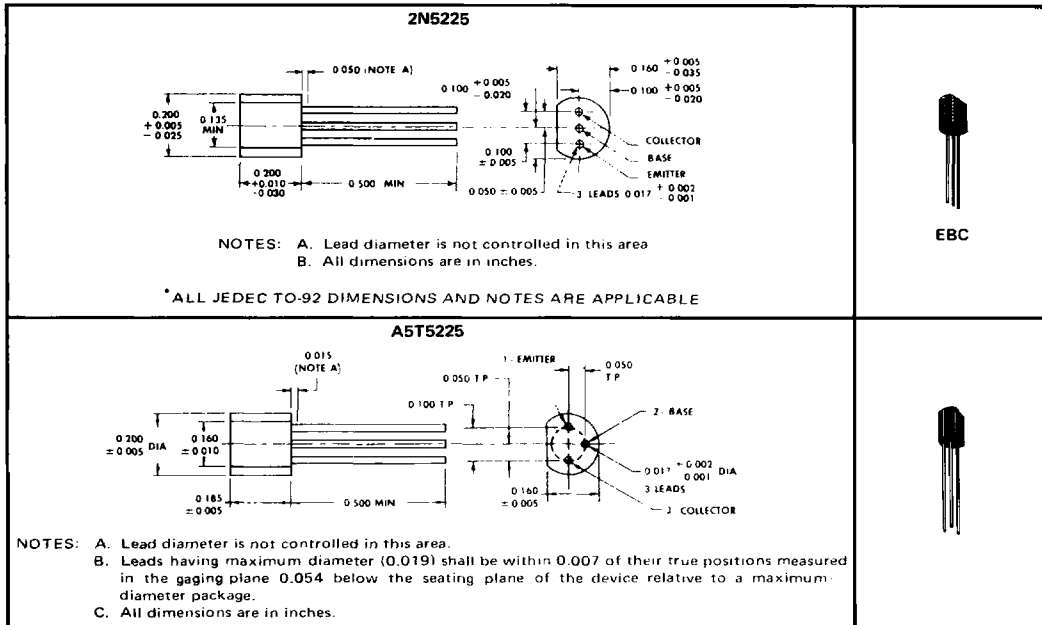
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SILECT[†] TRANSISTORS[‡] FOR MEDIUM-CURRENT AUDIO AMPLIFIER APPLICATIONS

- For Complementary Use with P-N-P Types 2N5226, A5T5226
- Rugged One-Piece Construction with In-Line Leads or Standard TO-18 100-mil Pin-Circle Configuration

mechanical data

These transistors are encapsulated in a plastic compound specifically designed for this purpose, using a highly mechanized process developed by Texas Instruments. The case will withstand soldering temperatures without deformation. These devices exhibit stable characteristics under high-humidity conditions and are capable of meeting MIL-STD-202C, Method 106B. The transistors are insensitive to light.



absolute maximum ratings at 25°C free-air temperature (unless otherwise noted)

Collector-Base Voltage	25 V*		
Collector-Emitter Voltage (See Note 1)	25 V*		
Emitter-Base Voltage	4 V*		
Continuous Collector Current	500 mA*		
Continuous Device Dissipation at (or below) 25°C Free-Air Temperature (See Note 2)	<table border="0"> <tr> <td>625 mW §</td> </tr> <tr> <td>310 mW*</td> </tr> </table>	625 mW §	310 mW*
625 mW §			
310 mW*			
Storage Temperature Range	<table border="0"> <tr> <td>-65°C to 150°C §</td> </tr> <tr> <td>-55°C to 135°C*</td> </tr> </table>	-65°C to 150°C §	-55°C to 135°C*
-65°C to 150°C §			
-55°C to 135°C*			
Lead Temperature 1/16 Inch from Case for 60 Seconds	<table border="0"> <tr> <td>260°C §</td> </tr> <tr> <td>230°C*</td> </tr> </table>	260°C §	230°C*
260°C §			
230°C*			

NOTES: 1. This value applies when the base-emitter diode is open-circuited.

2. Derate the 625-mW rating linearly to 150°C free-air temperature at the rate of 5 mW/°C. Derate the 310-mW (JEDEC registered) rating linearly to 135°C free-air temperature at the rate of 2.82 mW/°C.

*The asterisk identifies JEDEC registered data for the 2N5225 only. This data sheet contains all applicable registered data in effect at the time of publication.

[†]Trademark of Texas Instruments.

[‡]U.S. Patent No. 3,439,238.

[§]Texas Instruments guarantees these values in addition to the JEDEC registered values which are also shown.

USES CHIP N24

TYPES 2N5225, A5T5225

N-P-N SILICON TRANSISTORS

*electrical characteristics at 25°C free-air temperature

PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT
$V_{(BR)CBO}$	Collector-Base Breakdown Voltage	$I_C = 100 \mu A$, $I_E = 0$		25		V
$V_{(BR)CEO}$	Collector-Emitter Breakdown Voltage	$I_C = 10 \text{ mA}$, $I_B = 0$	See Note 3	25		V
$V_{(BR)EBO}$	Emitter-Base Breakdown Voltage	$I_E = 100 \mu A$, $I_C = 0$		4		V
I_{CBO}	Collector Cutoff Current	$V_{CB} = 15 \text{ V}$, $I_E = 0$			300	nA
I_{EBO}	Emitter Cutoff Current	$V_{EB} = 4 \text{ V}$, $I_C = 0$			500	nA
h_{FE}	Static Forward Current Transfer Ratio	$V_{CE} = 10 \text{ V}$, $I_C = 10 \text{ mA}$	See Note 3	25		
		$V_{CE} = 10 \text{ V}$, $I_C = 50 \text{ mA}$		30	600	
V_{BE}	Base-Emitter Voltage	$I_B = 10 \text{ mA}$, $I_C = 100 \text{ mA}$	See Note 3		1	V
$V_{CE(sat)}$	Collector-Emitter Saturation Voltage	$I_B = 10 \text{ mA}$, $I_C = 100 \text{ mA}$	See Note 3		0.8	V
h_{fe}	Small-Signal Common-Emitter Forward Current Transfer Ratio	$V_{CE} = 10 \text{ V}$, $I_C = 50 \text{ mA}$	$f = 1 \text{ kHz}$	30	1800	
f_T	Transition Frequency	$V_{CE} = 10 \text{ V}$, $I_C = 20 \text{ mA}$	See Note 4	50		MHz
C_{cb}	Collector-Base Capacitance	$V_{CB} = 5 \text{ V}$, $I_E = 0$	$f = 1 \text{ MHz}$, See Note 5		20	pF

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- NOTES: 3. These parameters must be measured using pulse techniques. $t_w = 300 \mu s$, duty cycle $\leq 2\%$.
4. To obtain f_T , the $|h_{fe}|$ response with frequency is extrapolated at the rate of -6 dB per octave from $f = 20 \text{ MHz}$ to the frequency at which $|h_{fe}| = 1$.
5. C_{cb} measurement employs a three-terminal capacitance bridge incorporating a guard circuit. The emitter is connected to the guard terminal of the bridge.

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THERMAL INFORMATION

DISSIPATION DERATING CURVE

